INSTRUMENTS AND CONTROL SYSTEMS

INDEX TO VOLUME 43, 1970

This index is a guide to titles, authors, and subjects or articles published during 1970. Indices to featured and advertised products appear in each monthly issue.

Note: numbers in boldface type refer to the month of issue.

SUBJECT

Acoustic 2:75; 9:112; 12:71
Analog 1:101; 2:81; 3:97; 5:36, 113, 115, 124; 7:65, 67, 73; 8:39; 9:82, 117; 10:101; 12:87
Analytical 1:22, 77; 3:26; 4:123, 127; 5:118; 9:30, 112; 12:23
Calibration 1:77; 4:109, 114; 8:73; 9:96; 10:82
Circuits 3:107, 113; 4:42; 6:118; 7:28, 79, 85; 8:39, 41, 107; 9:33; 10:98
Components 1:24, 2:58, 91; 3:32; 4:91; 5:24, 26, 89, 97, 101, 122; 6:34, 99, 106,131; 8:39, 75, 83, 93, 107; 9:28, 33, 99, 109, 115, 117, 123, 129; 10:77; 12:75, 83
Computer 1:70; 3:81, 101, 123, 125; 4:30, 105, 131; 5:34, 81, 89, 97, 128; 6:121, 125, 127, 131; 7:20, 89, 93; 8:30, 35, 101, 103, 107, 110; 9:34, 82, 117, 121, 125, 129; 10:46, 101, 105, 115, 117, 121; 11:22, 25, 84-D3, 84-D9, 103, 109, 116; 12:18
Control 1:14, 20, 65, 97; 2:42, 75; 3:28, 101, 110; 4:30, 32, 35; 5:24, 34, 81, 105, 122; 6:34, 39, 42; 7:20, 89, 93; 8:30, 35, 93, 101; 9:82, 96, 99; 10:46, 115, 117; 11:22, 116; 12:18, 20, 26
Data 1:18; 3:30, 81, 125; 4:105; 5:21, 124, 128; 6:127; 7:18, 22, 65, 67, 73, 83; 8:110; 10:105, 121; 11:84-D3, 84-D9, 103, 109; 12:87
Digital 1:18, 97; 2:91; 3:30, 101; 4:105; 5:21, 32, 34, 81, 89, 97, 124, 128; 6:121, 127, 131; 7:18, 20, 22, 28, 89; 8:30, 89, 103; 10:121; 12:26
Display 1:20; 3:28, 81, 86; 7:73; 8:32; 11:84-D3, 84-D9, 109
Electrical 1:24; 2:63, 67; 4:101; 5:36, 113, 116; 8:33, 110; 7:85; 9:99; 10:95
Electronic 2:72; 3:107, 113; 4:119; 5:24, 122; 6:93; 9:33, 87; 10:35, 77, 90; 12:91
Fluid 1:16, 22, 85, 89, 108, 113; 2:85; 3:32, 4:32, 35, 91, 109, 114, 119, 127; 5:101, 105; 6:99, 106, 7:27, 85; 8:41, 73, 75, 79, 87; 9:28; 10:38, 73, 82; 12:23
Fluidics 2:75; 4:32, 123; 5:101, 103; 6:99
Hardware 1:16, 85, 89, 113; 3:97, 110; 5:105; 6:39, 110; 10:105, 117; 11:116; 12:79
Hydraulics 5:26; 8:79, 96
Information 4:131; 8:32; 9:34
Instrumentation 1:18, 22, 77, 108, 113; 2:58, 63, 67, 81, 85, 91; 3:22, 26, 28, 32, 94, 113, 123, 125; 4:32, 35, 42, 109, 114, 119, 123, 127; 5:21, 36, 107, 110, 113, 118, 118, 127; 6:106, 113; 7:22, 27, 65, 67, 83; 8:41, 75, 79, 87, 89, 103, 110; 9:26, 28, 30, 87, 91, 112, 115, 125; 10:35, 36, 48, 73, 85, 90, 95, 115; 11:25, 121; 12:20, 23, 71, 79, 83, 91
Kinematic 2:81; 5:110; 9:125
Logic 10:77
Mathematical 1:70, 97, 101; 7:77, 79, 83; 8:96; 9:109; 10:82, 98; 12:75, 87
Mechanical 4:42; 5:107, 127; 6:110, 118, 125; 8:83, 96; 9:109, 115, 129; 11:25, 26; 12:18, 71, 75, 79, 83
Optical 3:26, 94, 110; 5:110; 9:91; 10:36
Process 1:14, 65, 70, 89; 4:30, 91; 5:107, 116, 118; 6:96; 7:93; 8:101; 9:30; 10:46, 48, 73, 11:22, 12:26
Simula[illegible]1:101; 5:115; 7:77; 9:121; 10:101
Softw[illegible]4; 9:34; 11:103
Standards 3:97; 10:38, 85, 90, 95; 11:121; 12:91
Thermal 2:63, 85; 5:103, 127; 6:33, 34, 42, 96; 8:89; 9:91, 96; 10:48

TITLE

Acoustic Fluidic Sensor 2:75
Adaptive Process Control by Pattern Recognition 3:101
Analog Computers in Process Applications 9:82
Analog Controller Simulation 5:115
Analog Data Acquisition 7:65
Analog-to-Digital Conversion 5:89
Analog-to-Digital Conversion, Part 2: Conversion Techniques 6:131
Analytical Mass Spectrometer Calibration of Standard Leaks 8:73
Analyzing Signals for Information, Part 1: Probability 12:87
Annunciator Systems 1:20
Anticipatory Proportioning 8:42
Arc Emission Simulation 1:101
Automatic Guidance of Earth Boring Augers 3:110

CRT Phosphor Selector 3:86
CRT Process Displays 3:22
Cage Trim Control Values 5:105
Cam Shape Synthesis 9:109
Carbon Brush Performance Measurements 6:110
Carbon Monitor 1:22
Centaur, The 9:4
Potentiometric pH Measurements 9:30
Precision Pressure Measurements 10:73
Precision Random Event Scaler 2:72
Precision Timing Systems, Part 1: Standard Scales 9:87
Precision Timing Systems, Part 2: Stable Clock 10:90
Precision Timing Systems, Part 3: Performance 11:121
Precision Timing Systems, Part 4: Implementation and Operation 12:91
Pressure Transducers 9:28
Primary Gas Standards 10:38
Process Control Software 1:14
Process Identification Method 8:121
Process Measurements by Sound Velocimetry 9:112
Processor-Controlled Data Acquisition 3:123
Program Controller Review 9:99

Rational Machine, The 3:4
Recording Controller 3:28
Remote Strain Measurement 4:42
Remote Temperature Measurements 8:96
Resistor Ladders for Digital-to-Analog Conversion 8:107
Road, The 7:4
Rotating Machine, The 5:4

SCR Control of Saturable Reactors 8:93
Sampled Data Reconstruction Errors 8:127
Sampling Valve Survey 1:89
Shaded Pole Motor Speed Control 6:118
Signal Flow Graph Primer 7:79
Simulation Analysis with Interactive Computer Graphics 11:109
Sizing Control Valves for Flashing Service 1:85
Solids Flow Meter 5:107
Split-Film Anemometer Sensors 6:106
Strong Eagles 11:4
System Graphing Concepts 7:77

Temperature-Independent Relative Humidity Sensor 8:41
Temperature Measurements by Infrared Radiation 9:91
Temperature, Pressure, and Flow Direction Probe 1:108
Thermal Mass Flowmeter 2:85
Thermal Strain Measurement 5:127
Thermal Testing of Hydraulic Machinery 8:96
Thermionic Conversion 8:33
Thermocouple Linearizing Circuit 9:96
Thermoelectric Devices 8:34
Three Dimensional Multi-Channel Display 7:73
Time-Shared Computers in Experimental Environments 10:105
Time Sharing Report 5:128
Transient Response Approximations 10:98
Transient Synthesis for Mechanical Testing 9:125
Transistorized DC Motor Control 5:122
Transmission Cable Optimization 10:95
Transmission Line Fundamentals 4:101

Ultrasonic Thickness Measurements 12:71
Universal Sorption Gas Analyzers 5:118
Untunable Loops 10:46

VVR Analog Multipliers 8:39
Valve Positioners 1:16
Vibrating Spool Densitometer 1:113
Vibrating Wire Tranaducer 2:58
View from Peru, A 12:20

Whatever Happened to Fluidics 4:32

X-Ray Laminography 3:94

AUTHOR

Adams, W. S. 3:113; 8:39; 9:117
Adkins, D. E. 3:110
Agar, J. 1:113
Alsopp, H. J. 4:119
Amendola, F. 7:28
Arrendale, H. 10:73

Baker, W. C. 2:85
Ballato, A. 2:67
Beeken, B. B. 2:75
Begley, W. W. 9:87; 10:90; 11:121; 12:91
Bell, R. E. 3:86
Bell, T. E. 91:109
Benson, J. A. 2:85
Bergendahl, T. A. 4:105
Bernard, B. 10:36
Black, L. W. 12:23
Blackletter, D. O. 9:109
Bodle, R. L. 10:35
Boger, H. W. 1:85
Bosso, F. C. 9:34; 11:25
Botsco, R. 5:116
Boucher, F. R. 1:22
Bristol, E. H. 3:101
Bristol, H. R. 3:28
Brueschke, E. E. 7:73
Bryan, J. W. 11:26
Bulkley, D. D. 9:91
Bullis, W. M. 10:105
Burke, R. H. 1:97

Campagnuolo, C. J. 8:99; 8:83
Chan, S. H. 8:41
Cole, K. M. 1:77
Costa, D. P. 4:101
Crawford, F. 8:39; 9:117
Crossley, F. L. 2:81

D'Auteuil, R. J. 8:113
de Brea, C. 1:18
DeLuca, P. V. 1:24
Dennis, L. P. 10:121
Dillon, J. A. 5:32; 6:33; 7:18; 9:30; 10:48; 12:18
Dobie, A. B. 6:110
Donovan, J. C. 10:95
Dudzinski, T. J. 1:108
Dunwoody, S. 8:32

Easter, E. 2:85
Easton, S. S. 10:77
Englund, D. R. 2:63
Esser, F. J. 10:95
Coherent Noise in Low-Level Sampled Data Systems 8:110
Computer Control Outlook 11:22
Computer Controlled Instrumentation Amplifier 10:115
Computer Controlled Test System 11:25
Computer in Mechanical Testing 8:125
Computers in Process Control: Panel Discussion 8:81
Computer Word Formats 9:34
Continuous Batch Monitoring 12:26
Continuous Blending Systems 4:32
Continuous Monitoring of Diesel Exhaust 4:127
Continuous Monitoring of Suspended Solids 7:27
Core Memory Systems 4:105
Creative Doodling Made Easy, CRT Terminals 11:84-D3
Crystal Parameter Measurement 2:67

DDC—The Inherent Difference 7:89
DDC Output Stations 1:97
Data Acquisition System Review 3:125
Data Display, Part 1: System Characteristic 3:81
Data Display, Part 2: System Hardware 4:131
Density Measurement of Solid Objects 12:23
Detection of Ball Bearing Malfunctions 12:79
Daus Ex Machina 1:4
Differential Thermistor Anemometer 3:32
Differential Voltmeter, The 8:113
Digital Coding Matrix 3:30
Digital Coding Systems 8:32
Digital Computers In Process Control 4:30
Digital Control Seminar 8:35
Digital Magnetic Storage 7:22
Digital Position Measurement 9:129
Digital Pressure System Review 8:87
Digital Recording 1:18
Digital Rotary Encoder Review 5:97
Digital to Pneumatic Transducer 1:85
Digital Thermometer Review 8:89
Digitally Controlled Function Synthesizer 8:103
Digitization of Graphical Analog Records 10:121
Direct Numerical Control 12:18
Dynamic Calibration of Turbine Flowmeters 4:109
Dynamic Force Measurement Techniques, Part 1: Dynamic Compensation 2:81
Dynamic Response Determination by On-Line Correlation 7:83
Electronic Control Meters 4:35
Electronic Counter Survey 2:91
Electronic Load Cell Review 12:83
Error Reduction in Potentiometers 6:113

FET Conductance Measurements 9:117
Fast Response Electrohydraulic Servo System 3:97
Fast Response Pirani Gage 4:119
Flueric Sensor RF-Induced Currents 5:103
Fluidic Elements In Hydraulic Oil 5:26
Fluidic Oscillators 6:99
Fluidic Output Impedance 5:101
Frequency and Time Standard Review 10:85

Gage Length Effects on Strain Measurements 9:115

Helmsmen, The 12:4
Hierarchical Computer Control Systems, Part 1: System Organization 10:117
Hierarchical Computer Systems Part 2: Subsystem Configuration 11:116
High-Speed Rotary Switch 1:24
Hot Film Probes in Water-Contaminated Flow 4:114
Hot-Wire Anemometer Calibration Sensors 10:82
Humidity Calibration Techniques 1:77
Hydrostatic Liquid Level Measurements 8:79

IC Noise Immunity Measurements 10:77
IEEE Show Preview 2:119
ISA Show Preview 9:26
Improving Performance of Digital Controllers 1:70
Industrial Air Filter Survey 4:91
Industrial Applications of Adaptive Control 7:93
Industrial Cryogenics 10:48
Infinite Min, The 9:30
Inkography 11:26
Instrumentation Tape Recorder Review 7:87
Interactive CRT Terminal Review 11:84-D9
Interactive Computer Languages 11:103
Interferometric Displacement Indication 5:110
Intermittent Component Detector 9:33
Iron Horse, The 8:4
Is Reset Action Always Necessary 2:42
Is Reset Windup a Misnomer 9:34
Isolated Instrumentation Amplifier 10:35

Justification of Process Control Computers 5:34

Keyboard Encoding Systems 7:28

Laser Operation 10:36
Level and Density Control 4:123
Liquid Chromatography Detector 3:26
Loading Effects in Measurement Systems 2:63
Long Delay Monostable Timer 5:24
Low-Frequency A-D Input Systems 5:124
Low Frequency Noise Source 3:113

Magnetohydrodynamic Power Generation 7:85
Manufacture of Power, The 2:4
Matrix Board Programmers 6:39
Measurement Noise 5:36
Measuring Excess Noise of Microwave Devices 3:107
Mechanical Impedance Concepts 12:75
Memories in Instrumentation 5:21
Microwave Moisture Measurement 5:116
Miniature Pressure Transducer 8:75
Modified PI Algorithm for Process Control 8:101

Ned Ludlam Lives 4:4
New Advocate, The 6:4
New Approach to In-Plant Training 8:32
New Kind of Art, A 10:4
Non-Linear Function Generator 9:121

On-Line Control at SJCC 7:20
Optical Memory Systems 7:18
Optimal Telephone Call, The 12:24

Parameter Optimization by Analog Computer 10:101
Pneumatic-to-Electrical Converter 8:83
Faucett, T. R. 8:127
Favour, J. D. 9:125
Fenton, N. 4:42; 8:96
Fieldhouse, K. N. 12:75
Franklin, R. N. 2:58
Freymuth, P. 10:82
Furbush, J. M. 4:123

Gibbes, D. 8:42
Glawe, G. E. 1:108
Gold, M. I. 10:98
Gordon, H. F. 8:39
Grader, J. 9:82
Gudaz, J. A. 7:93

Haspert, J. K. 5:103
Holben, E. F. 1:85
I & CS Staff, 1:89; 2:91, 119; 3:125; 4:91; 5:97, 128; 7:67; 8:35, 87, 89; 9:26, 99; 10:85; 11:22, 84-D9; 12:83
Inaloglu, G. F. 3:101

Kalb, H. T. 2:81
Kaufman, E. N. 8:75
Keyes, M. A. 7:93
Kingdon, S. P. 9:121
Koenig, A. L. 10:105
Krause, L. N. 1:108
Krigman, A. 1:4; 2:4; 3:4; 4:4; 5:4, 81; 6:4; 7:4; 8:4; 9:4; 10:4; 11:4; 12:4
Krishnaiyer, R. 5:101; 10:95

Laird, J. R. 5:21
Lamb, L. T. 12:
Lang, H. W. 4:127
Langenthal, I. M. 12:87
Laurin, M. 1:20
Lawford, V. N. 8:79
Lay, C. M. 8:110
Layden, P. 2:87
LeBrun, J. M. 9:125
Lehnhoff, T. F. 5:127
Lesco, D. J. 1:101
Loesberg, P. P. 5:124
London, A. L. 8:96
Luce, A. N. 9:33

MacArthur, G. 7:28
Mahan, R. E. 3:81; 4:131
Mancuso, S. 12:26
Martin, R. L. 12:79
Martincavage, J. 9:96
Mason, T. M. 8:73
McDonald, J. 7:65
McMillin, B. E. 4:123
Mehta, K. S. 3:30; 5:24
Maloni, A. 4:32; 9:34; 7:22; 9:28
Marceret, F. J. 4:114
Mewett, R. J. 8:113
Miller, J. G. 7:89; 8:30
Moler, R. B. 3:94
Moore, C. F. 1:70; 4:30; 8:32
Muller, J. T. 5:105
Murphy, R. J. 2:58
Murrill, P. W. 8:101, 12:20

Nelson, D. V. 8:96
Newman, D. R. 12:71
Nisenfeld, A. E. 5:115
Nolte, C. B. 5:107

Ohlson, G. F. 9:121
Olin, J. C. 8:106

Pattison, R. J. D. 6:110
Paynter, H. M. 7:77
Pearson, J. B. 11:26
Pendarvis, M. T. 8:93
Pike, J. M. 3:32
Pottinger, M. 9:115
Pyke, T. N. 10:105

Quick, H. C. 4:35

Rasmussen, H. 11:84-D3
Rathore, T. S. 3:30
Reger, J. A. 1:77
Reiner, R. L. 8:103
Renschler, E. L. 5:89; 6:131; 8:107
Rispoli, L. M. 10:117; 11:116
Rovira, A. A. 8:101

Sampson, J. M. 9:82
Sass, W. H. 11:84-D3
Scornavacca, F. 10:38
Shapiro, A. H. 9:87; 10:90; 11:121; 12:91
Sheets, W. R. 5:122
Sheheen, S. J. 6:118; 7:27
Shibla, C. L. 2:67
Shuster, T. E. 9:110
Slawson, R. S. 8:34
Smith, C. L. 2:42; 5:34; 7:20; 8:101; 10:48
Smith, D. H. 5:26
Smith, J. H. 6:125
Sperrazza, J. L. 10:115
Steadman, J. F. 3:101
Stevens, G. H. 4:109
Straub, W. F. 3:107
Subhani, K. F. 3:113
Swain, W. H. 7:79

Taylor, J. H. 8:110
Thomas, R. H. 12:24
Thurber, R. W. 10:105
Townes, H. W. 9:109
Tsien, H. C. 5:118

Ulmer, F. H. 10:105

vanDick, R. C. 2:72
Vajo, V. S. 10:101
Vecchio, S. R. 8:41

Wait, J. V. 6:127
Waka, D. J. 11:103
Wanner, E. C. 1:16; 3:22; 4:32; 5:36
Watson, E. 3:26
Watts, R. C. 7:83
Wells, C. H. 6:121
Wiles, A. P. 9:129

Yerkes, A. 1:14

Zacharias, E. M. 9:112
Zeller, J. R. 3:97
Ziemke, C. M. 7:85
Ziman, G. C. 3:123